

Application of Surface Physics for Instruments in Space Science

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Abstract

Contents

| 1 | Intro | oduction | 1 |
|----|--------|---|----|
| 2 | The | ory | 3 |
| | 2.1 | Requirements | 3 |
| | 2.2 | Basic Theory about a TOF masspectrometry | 3 |
| | | 2.2.1 Principle | 3 |
| | | 2.2.2 Mass Calibration | 4 |
| | | 2.2.3 Mass resolution | 4 |
| | | 2.2.4 Sensitivity | 5 |
| | 2.3 | Ion Optical Design, NIM specific elements | 5 |
| | | 2.3.1 Ion-source | 6 |
| 3 | Setu | up | 7 |
| | 3.1 | NIM Instruments | 7 |
| | | 3.1.1 Prototype | 7 |
| | | 3.1.2 Protoflight Model | 7 |
| | 3.2 | Test facilities/ Test Tools | 7 |
| 4 | Exp | eriments | 9 |
| | 4.1 | | 9 |
| | | 4.1.1 Measurement Principle | 10 |
| | | 4.1.2 Discussion | 10 |
| | 4.2 | Prototype CASYMIR-D/-E | 10 |
| | 4.3 | Simulations | 10 |
| | 4.4 | Filament decision | 10 |
| | 4.5 | Pulser | 10 |
| | 4.6 | Detector Tests | 10 |
| | 4.7 | Ionoptics | 10 |
| | | 4.7.1 Voltage Optimisation | 10 |
| 5 | Con | nclusion | 11 |
| 6 | Out | look | 13 |
| Re | eferei | nces | 14 |
| | | | |
| 7 | App | pendix | 15 |

List of Acronyms

BCVD Boron-doped Chemical Vapour Deposition

DLC Diamond-Like Carbon surface

EMG Exponentially Modified Gaussian

ENA Energetic Neutral Atoms

FWHM Full Width at Half Maximum

IBEX Interstellar Boundary EXplorer

ILENA Imager for Low Energetic Neutral Atoms

IMAP Interstellar Mapping and Acceleration Probe

JVIA Jovian Neutral Atom Analyser

JUICE JUpiter ICy moon Explorer

L1 Lagrange 1

LISM Local InterStellar Medium

MCA MultiChannel Analyzer

MCP MultiChannel Plate

PA PostAcceleration voltage

PEP Particle Environment Package

RPA Retarding Potential Analyser

1 Introduction

JUICE PEP NIM

2 Theory

2.1 Requirements

2.2 Basic Theory about a TOF masspectrometry

2.2.1 Principle

This chapter explains the function of a TOF instruments. A TOF mass spectrometer consists of, an ion-source, a mass analyser and a detector. The mass analyser has an ion-mirror which increases the flight distance of the ions by keeping the instrument on a certain length. A longer flight distance increases the mass resolution of the instrument.

In the ion source, the ions are produced. An electric field in the source is generated such that ions get trapped in it. Then ions get accelerated by applying a high voltage pulse on the extraction grid. Include a Graphic of the IS and draw a sample electric field to explain how the extraction pulse (the door to open) works. If the pulse width is long enough that all ions leave the source during the time the pulse is applied, the ions get all the same amount of energy W

$$W = \int_0^{s_0} q_0 E_s ds = q_0 U_0 \tag{1}$$

With s_0 the distance the ions get accelerated, in our case 1mm which is half the height of the ion source, q_0 the elementary charge, E_s the applied electric field strength and U_0 the voltage applied on the extraction grid. This energy is equal to the kinetic energy the ions have after leaving the ion-source

$$q_0 U_0 = \frac{1}{2} m v^2$$
(2)

With m the mass of the particle and v the particle velocity. Rearranging this formula we get

$$\frac{m}{q_0} = 2U_0 \frac{t^2}{s^2} \tag{3}$$

With t the time of flight and s the flight distance. Therefore, m/q_0 is proportional to t^2 . Ions starting at different positions also get a different amount of energy. Ions starting closer to the extraction grid will get less energy than ions further away from the grid. At a certain point after the source, the ions with higher energy have overtaken the slower ions. This point is at around $2 \cdot s_0$ which corresponds to a very short flight distance. To shift this focal point onto to the detector, additional fields after the ion-source are applied.

The ions have different thermal energies. Therefore ions of the same mass and the the same starting position will not have all the same energy when they leave the ion source. This energy spread leads to a difference in their velocity and to different flight times. This energy spread can be partially compensated by an ion-mirror also referred to as reflectron (Fig. 1). Ions with a higher energy will penetrate deeper into the ion-mirror and have a bigger flight path than ions with less energy. Therefore, the ion-mirror is able to compensate the different start energies of the ions. In the worst case scenario we have one particle flying toward the extraction grid and

the other particle flying with the same velocity in the opposite direction. The second particle gets decelerated and has to turn in the source. When it reached its initial position, it has the same amount of energy as the first particle. But it will always be behind the first particle by a constant time delay needed to turn around and reach its initial position. To minimize this effect, one has to minimise the distance of the ionisation region or increase the voltage of the HV pulse. A smaller ion source means less ions and therefore less signal. Increasing the HV pulse results in bigger electronic noise at the start of the spectrum and fast species such as hydrogen of helium are lost in the noise.

2.2.2 Mass Calibration

In this section we discuss the calibration of the mass axis. According to Eq. (3) the m/q_0 is proportional to the square of time. By rearranging Eq. (3) m is:

$$m = 2q_0 U_0 \frac{t^2}{s^2} \tag{4}$$

Take together all parameters which remain constant to one single constant:

$$C = \frac{2q_0 U_0}{s^2}$$
 (5)

and considering the time scale has a constant offset t_0 , equation (4) results in

$$m = C(t - t_0)^2 \tag{6}$$

In this equation there are two free parameters, C and t_0 . To calibrate a mass spectrum at least two species appearing in the spectrum have to be known to solve this equation for the two parameters.

2.2.3 Mass resolution

The mass resolution is calculated as follows. According to Eq.6 m is:

$$m = c \cdot t^{2}$$

$$\frac{dm}{dt} = 2ct$$

$$dm = 2ct \cdot dt$$

$$\frac{m}{dm} = \frac{ct^{2}}{2ct \cdot dt}$$

Resulting in:

$$\frac{m}{\Delta m} = \frac{t}{2\Delta t} = \frac{\mu_t}{2FWHM_t} \tag{7}$$

With μ_t the centre of the mass peak in the time domain and $FWHM_t$ the full width at half maximum. The $FWHM_t$ depends on several parameters. For example the turn around time

of the particles, the energy spread resulting from different starting positions of the particles relative to the extraction grid, spread in thermal energy. The reflectron is able to compensate for the energy spread by a certain amount. There are also limitations of the instrument itself. For example the performance of the pulser which will be discussed later in Chap. bla.

2.2.4 Sensitivity an SNR

2.3 Ion Optical Design, NIM specific elements

A time of flight mass spectrometer consists of, an ion-source, a mass analyser and a detector.

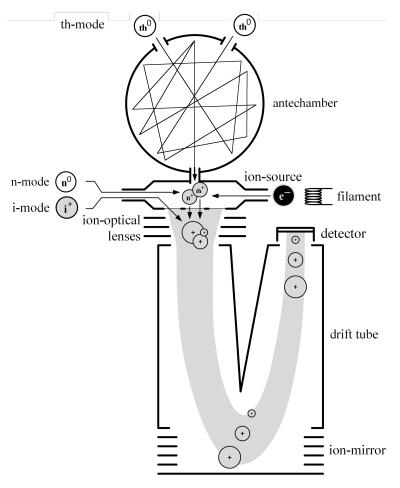


Figure 1: Schematics of the NIM mass spectrometer. Adapted from [2].

The NIM instrument is able to measure neutrals and ions. Neutral particles get ionised by electron ionisation. A filament is heated up until it emits electron. Ions enter the ion source directly. All ions then get accelerated to the same energy and fly through the mass analyser. Light particles fly faster through the spectrometer than heavier ones. The different particle species arrive at different times at the detector. To enlarge the flight distance, an ion-mirror,

which reflects the ions and leads them back to the detector. The used detector is a MCP detector.

2.3.1 Ion-source

To calculate the number of ions produced in the ion source we use:

$$I_{ion} = \beta \cdot Q_{ion} \cdot L \cdot n \cdot I_{em} \tag{8}$$

With β the extraction efficiency which is 1, L as the effective ionising path in our case 4 mm, n the particle density, I_{em} the electron emission current from the filament and Q_{ion} the ionising cross section. The cross sections of species used in our calibration can be found in table

3 Setup

- 3.1 NIM Instruments
- 3.1.1 Prototype
- 3.1.2 Protoflight Model
- 3.2 Test facilities/ Test Tools

4 Experiments

In this section, the different tests are described to develop the NIM instrument. Different parts of the instrument were tested to improve the instrument.

4.1 Reflectron

The NIM prototype reflectron was exchanged through the flight like reflectron, which was tested. The NIM prototype reflectron consisted of 12 ring electrodes connected with each other with resistors in between them. On the first, 5th and 12th electrode, a voltage can be applied. With the different resistors, a linear voltage gradient in the reflectron is generated. The flight reflectron consists of a ceramic tube with two resistance spirals on its inner walls. There are three electrodes, where the voltage can be applied. The electrodes are connected via resistance spirals with each other. The two reflectrons can be seen in Fig. 2. This kind of reflectron was also used in the RTOF mass spectrometer which flied in ROSINA [3] and the in the NGMS [1].

Therefore, the two reflectrons are from the electrical point of view the same.



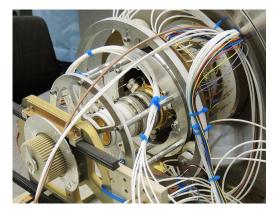


Figure 2: Left: Prototype reflectron with ringelectrodes. Right: Flight reflectron

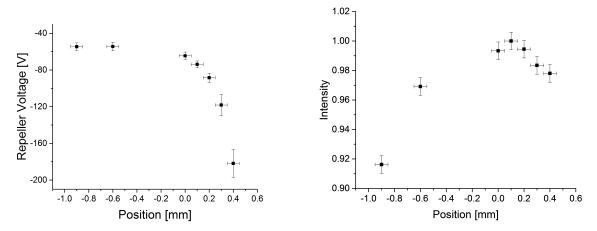


Figure 3: Left: The filament repeller voltage to reach the maximum electron intensity over the volume of the neutral particles. Right: Electron intensity normed on the intensity at position 0.

4.1.1 Measurement Principle

4.1.2 Discussion

4.2 Prototype CASYMIR-D/-E

4.3 Simulations

4.4 Filament decision

4.5 Pulser

4.6 Detector Tests

4.7 Ionoptics

4.7.1 Voltage Optimisation

Two types of electrical lenses. positive and negative voltage lenses. positive and negative voltage lenses have the same effect. In negative voltage lenses, the particles fly faster = shorter time-of-flight. This results in a better mass resolution.

Aim in the lab is to get two different voltage sets. One for positive voltages to not stress the equipment and one with negative voltage lenses to reach the maximal performance of the instrument. -¿ Tests showed no significant better mass resolution. A more detailed data analysis has to be made.

5 Conclusion

6 Outlook

References

- [1] L. Hofer. Development of the gas chromatograph mass spectrometer to investigate volatile species in the lunar soil for the Luna-Resurs mission. Universität Bern, 2015.
- [2] S. Meyer. <u>Development of a Neutral Gas-and Ion-Mass Spectrometer for Jupiter's Moons</u>. Universität Bern, 2017.
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7 Appendix

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<u>Erklärung</u>

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